

# AO4484 40V N-Channel MOSFET

## **General Description**

The AO4484 uses advanced trench technology to provide excellent  $R_{\text{DS(ON)}}$  with low gate charge. This is an all purpose device that is suitable for use in a wide range of power conversion applications.

## **Product Summary**

 $V_{DS}(V) = 40V$ 

 $I_D = 10A$   $(V_{GS} = 10V)$ 

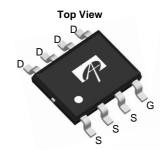
 $R_{DS(ON)} < 10 m\Omega \qquad (V_{GS} = 10 V)$ 

 $R_{DS(ON)} < 12m\Omega$   $(V_{GS} = 4.5V)$ 

100% UIS Tested 100% Rg Tested









Absolute Maximum Ratings T<sub>J</sub>=25℃ unless otherwise noted

Parameter		Symbol	10 Sec	Steady State	Units	
Drain-Source Voltage		$V_{DS}$	40		V	
Gate-Source Voltage		$V_{GS}$	±20		V	
Continuous Drain	T <sub>A</sub> =25℃		13.5	10		
Current <sup>A</sup>	T <sub>A</sub> =70℃	$I_{D}$	10.8	8	۸	
Pulsed Drain Current B		I <sub>DM</sub>	120		А	
Avalanche Current <sup>G</sup>		I <sub>AR</sub>	23			
Repetitive avalanche energy L=0.3mH <sup>G</sup>		E <sub>AR</sub>	79		mJ	
Power Dissipation <sup>A</sup>	T <sub>A</sub> =25℃	О	3.1	1.7	W	
	T <sub>A</sub> =70℃	$-P_D$	2.0	1.1	VV	
Junction and Storage Temperature Range		$T_J, T_{STG}$	-55 to 150		C	

Thermal Characteristics							
Parameter	Symbol	Тур	Max	Units			
Maximum Junction-to-Ambient A	t ≤ 10s		31	40	€/M		
Maximum Junction-to-Ambient A	Steady State	$R_{ heta JA}$	59	75	°C/W		
Maximum Junction-to-Lead <sup>C</sup>	Steady State	$R_{\theta JL}$	16	24	℃/W		

### Electrical Characteristics (T<sub>J</sub>=25℃ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Тур	Max	Units			
STATIC PARAMETERS									
$BV_{DSS}$	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	40			V			
	Zero Gate Voltage Drain Current	$V_{DS} = 40V, V_{GS} = 0V$			1				
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	T <sub>J</sub> = 55℃			5	μΑ			
I <sub>GSS</sub>	Gate-Body leakage current	$V_{DS} = 0V, V_{GS} = \pm 20V$			±100	nA			
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS} I_D = 250\mu A$	1.7	2.2	3	V			
I <sub>D(ON)</sub>	On state drain current	$V_{GS} = 10V, V_{DS} = 5V$	120			Α			
		$V_{GS} = 10V, I_D = 10A$		8.2	10				
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	T <sub>J</sub> =125℃		12.5	16	mΩ			
		$V_{GS} = 4.5V, I_D = 8A$		10	12.5				
<b>9</b> FS	Forward Transconductance	$V_{DS} = 5V, I_{D} = 10A$		75		S			
$V_{SD}$	Diode Forward Voltage	$I_S = 1A, V_{GS} = 0V$		0.72	1	V			
Is	Maximum Body-Diode Continuous Curr			2.5	Α				
DYNAMIC	PARAMETERS								
C <sub>iss</sub>	Input Capacitance	,		1500	1950	pF			
C <sub>oss</sub>	Output Capacitance	$V_{GS}$ =0V, $V_{DS}$ =20V, f=1MHz		215		pF			
$C_{rss}$	Reverse Transfer Capacitance			135		pF			
$R_g$	Gate resistance	$V_{GS}$ =0V, $V_{DS}$ =0V, f=1MHz	2	3.5	5	Ω			
SWITCHII	NG PARAMETERS								
Q <sub>g</sub> (10V)	Total Gate Charge			27.2	37	nC			
Q <sub>g</sub> (4.5V)	Total Gate Charge	V -10V V -20V I -10A		13.6	18	nC			
$Q_{gs}$	Gate Source Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =20V, I <sub>D</sub> =10A		4.5		nC			
$Q_{gd}$	Gate Drain Charge			6.4		nC			
t <sub>D(on)</sub>	Turn-On DelayTime	ALL Y		6.4		ns			
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =10V, $V_{DS}$ =20V, $R_L$ = $2\Omega$ ,		17.2		ns			
$t_{D(off)}$	Turn-Off DelayTime	$R_{GEN}=3\Omega$		29.6		ns			
t <sub>f</sub>	Turn-Off Fall Time		_	16.8		ns			
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =10A, dI/dt=100A/μs		30	40	ns			
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =10A, dI/dt=100A/μs		19		nC			

A: The value of R  $_{6JA}$  is measured with the device mounted on  $1\text{in}^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25$ °C. The value in any given application depends on the user's specific board design.

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B: Repetitive rating, pulse width limited by junction temperature.

C. The R  $_{\theta JA}$  is the sum of the thermal impedence from junction to lead R  $_{\theta JL}$  and lead to ambient.

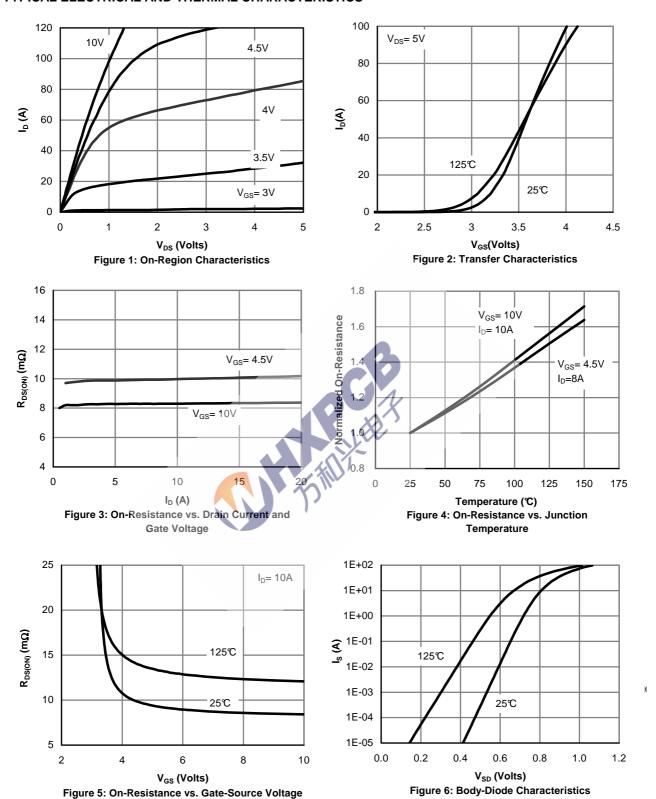
D. The static characteristics in Figures 1 to 6 are obtained using t  $\le$  300 $\mu$ s pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25℃. The SOA curve provides a single pulse rating.

F. The current rating is based on the  $t \leqslant 10\text{s}$  thermal resistance rating.

G.  $E_{AR}$  and  $I_{AR}$  ratings are based on low frequency and duty cycles to keep  $T_j$ =25C.

### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



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